

January 2002

**40A, 100V, 0.055 Ohm, N-Channel Power MOSFET**

This N-Channel enhancement mode silicon gate power field effect transistor is an advanced power MOSFET designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA17431.

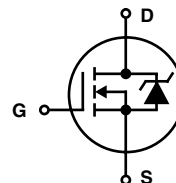
**Ordering Information**

PART NUMBER	PACKAGE	BRAND
IRFP150	TO-247	IRFP150

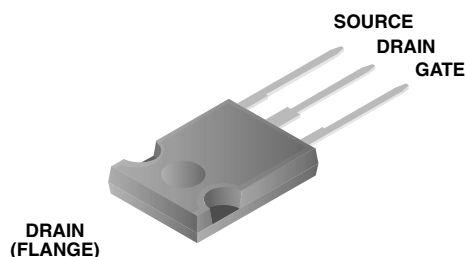
NOTE: When ordering, include the entire part number.

**Features**

- 40A, 100V
- $r_{DS(ON)} = 0.055\Omega$
- Single Pulse Avalanche Energy Rated
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

**Symbol****Packaging**

JEDEC STYLE TO-247  
TOP VIEW



# IRFP150

## Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

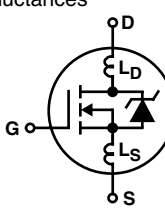
	IRFP150	UNITS
Drain to Source Voltage (Note 1) . . . . .	$V_{DS}$ 100	V
Drain to Gate Voltage ( $R_{GS} = 20\text{k}\Omega$ ) (Note 1) . . . . .	$V_{DGR}$ 100	V
Continuous Drain Current . . . . .	$I_D$ 40	A
$T_C = 100^\circ\text{C}$ . . . . .	$I_D$ 26	A
Pulsed Drain Current (Note 3) . . . . .	$I_{DM}$ 160	A
Gate to Source Voltage . . . . .	$V_{GS}$ $\pm 20$	V
Maximum Power Dissipation . . . . .	$P_D$ 180	W
Linear Derating Factor . . . . .	1.44	W/ $^\circ\text{C}$
Single Pulse Avalanche Energy Rating (Note 4) . . . . .	$E_{AS}$ 150	mJ
Operating and Storage Temperature . . . . .	$T_J, T_{STG}$ -55 to 150	$^\circ\text{C}$
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s. . . . .	$T_L$ 300	$^\circ\text{C}$
Package Body for 10s, See Techbrief 334 . . . . .	$T_{pkg}$ 260	$^\circ\text{C}$

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

### NOTE:

- $T_J = 25^\circ\text{C}$  to  $125^\circ\text{C}$ .

## Electrical Specifications $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$ (Figure 10)	100	-	-	V
Gate to Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	2.0	-	4.0	V
Zero-Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = \text{Rated } BV_{DSS}, V_{GS} = 0\text{V}$	-	-	25	$\mu\text{A}$
		$V_{DS} = 0.8 \times \text{Rated } BV_{DSS}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$	-	-	250	$\mu\text{A}$
On-State Drain Current (Note 2)	$I_{D(ON)}$	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}, V_{GS} = 10\text{V}$	40	-	-	A
Gate to Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20\text{V}$	-	-	$\pm 100$	nA
Drain to Source On Resistance (Note 2)	$r_{DS(ON)}$	$V_{GS} = 10\text{V}, I_D = 22\text{A}$ (Figures 8, 9)	-	0.045	0.055	$\Omega$
Forward Transconductance (Note 2)	$g_{fs}$	$V_{DS} \geq 20\text{V}, I_D = 20\text{A}$ (Figure 12)	13	20	-	S
Turn-On Delay Time	$t_{D(ON)}$	$V_{DD} = 50\text{V}, I_D = 40\text{A}, R_{GS} = 6.8\Omega, R_L = 1.2\Omega$ MOSFET Switching Times are Essentially Independent of Operating Temperature	-	15	24	ns
Rise Time	$t_r$		-	140	210	ns
Turn-Off Delay Time	$t_{D(OFF)}$		-	60	89	ns
Fall Time	$t_f$		-	90	140	ns
Total Gate Charge (Gate to Source + Gate to Drain)	$Q_{g(TOT)}$	$V_{GS} = 10\text{V}, I_D = 40\text{A}, V_{DS} = 0.8 \times \text{Rated } BV_{DSS}$ . $I_{g(REF)} = 1.5\text{mA}$ (Figure 14) Gate Charge is Essentially Independent of Operating Temperature	-	70	110	nC
Gate to Source Charge	$Q_{gs}$		-	20	-	nC
Gate to Drain "Miller" Charge	$Q_{gd}$		-	30	-	nC
Input Capacitance	$C_{ISS}$	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}, f = 1.0\text{MHz}$ (Figure 11)	-	2000	-	pF
Output Capacitance	$C_{OSS}$		-	1000	-	pF
Reverse-Transfer Capacitance	$C_{RSS}$		-	350	-	pF
Internal Drain Inductance	$L_D$	Measured from the Drain Lead, 6mm (0.25in) from the Package to the Center of the Die	Modified MOSFET Symbol Showing the Internal Devices Inductances 		-	nH
Internal Source Inductance	$L_S$	Measured from the Source Lead, 6mm (0.25in) from the Header to the Source Bonding Pad	-	12.5	-	nH
Junction to Case	$R_{\theta JC}$		-	-	0.70	$^\circ\text{C/W}$
Junction to Ambient	$R_{\theta JA}$	Free Air Operation	-	-	30	$^\circ\text{C/W}$

## Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	$I_{SD}$	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Diode	-	-	40	A
Pulse Source to Drain Current (Note 3)	$I_{SDM}$		-	-	170	A
Source to Drain Diode Voltage (Note 2)	$V_{SD}$	$T_J = 25^\circ\text{C}$ , $I_{SD} = 40\text{A}$ , $V_{GS} = 0\text{V}$ (Figure 13)	-	-	2.5	V
Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ\text{C}$ , $I_{SD} = 40\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	98	-	530	ns
Reverse Recovered Charge	$Q_{RR}$	$T_J = 25^\circ\text{C}$ , $I_{SD} = 40\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	0.41	-	2.5	$\mu\text{C}$

### NOTES:

- Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .
- Repetitive Rating: Pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
- $V_{DD} = 10\text{V}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 170\mu\text{H}$ ,  $R_G = 50\Omega$ , Peak  $I_{AS} = 40\text{A}$ .

## Typical Performance Curves Unless Otherwise Specified

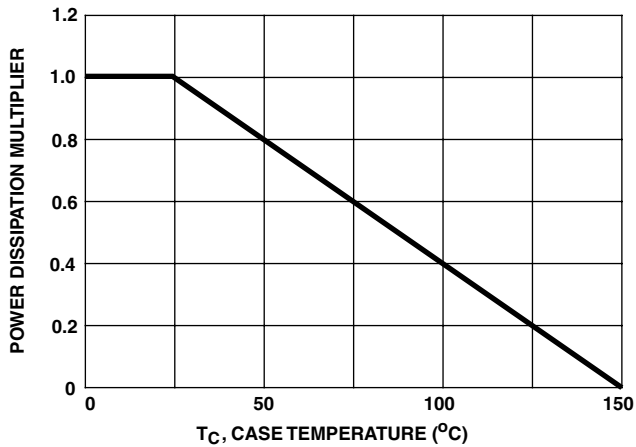


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

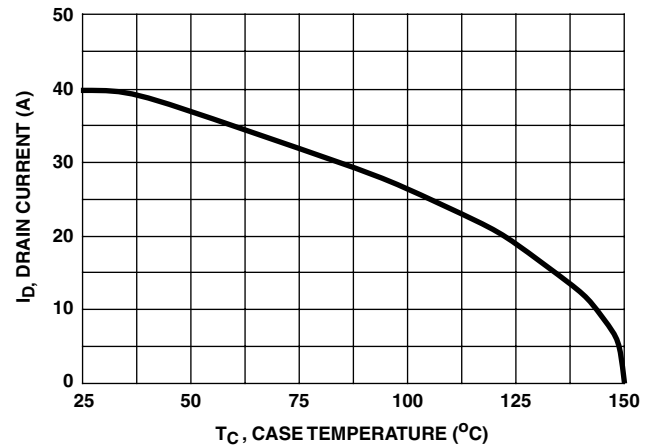


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

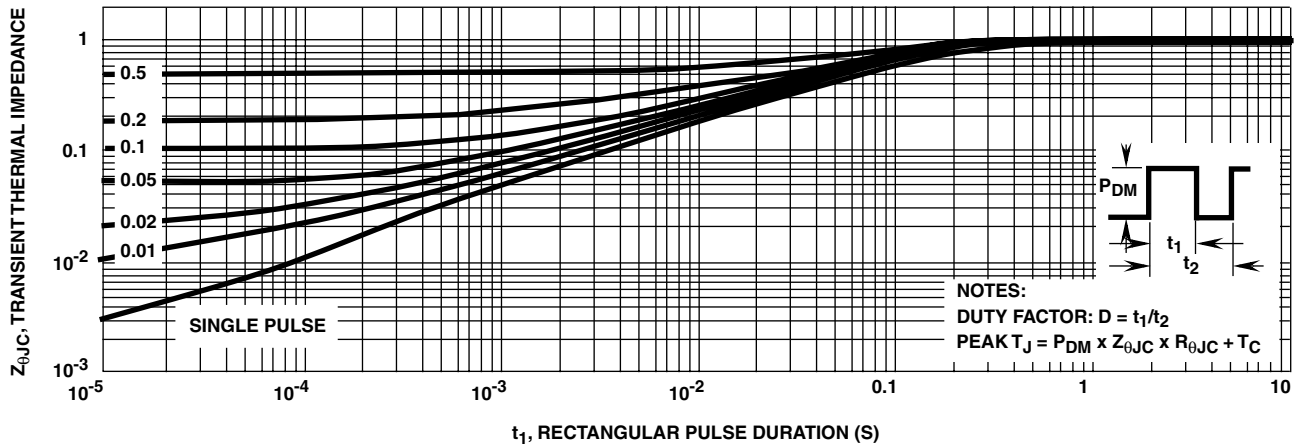


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

**Typical Performance Curves** Unless Otherwise Specified (Continued)

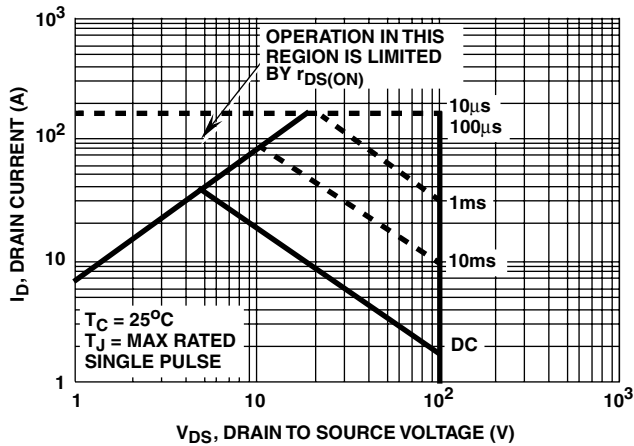


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

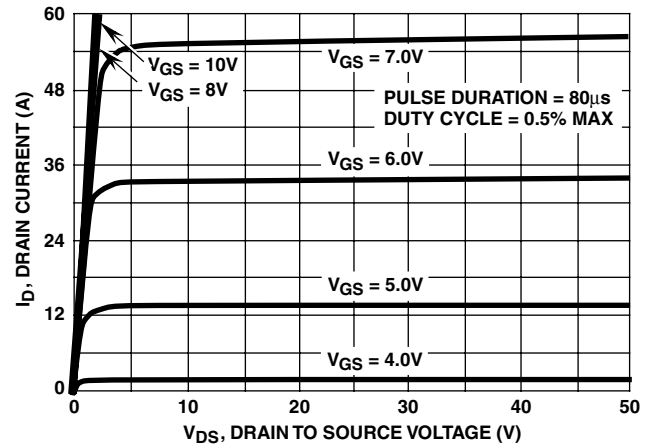


FIGURE 5. OUTPUT CHARACTERISTICS

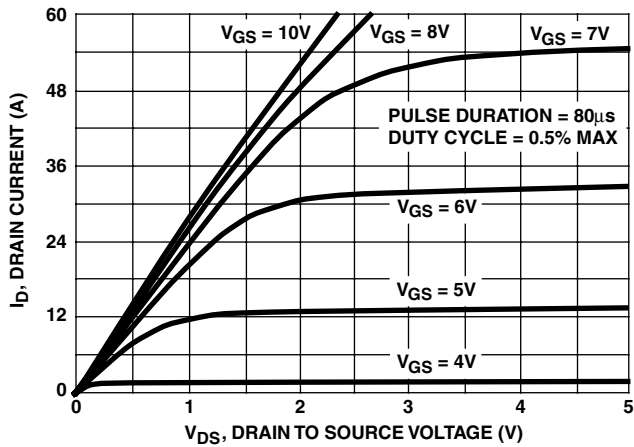


FIGURE 6. SATURATION CHARACTERISTICS

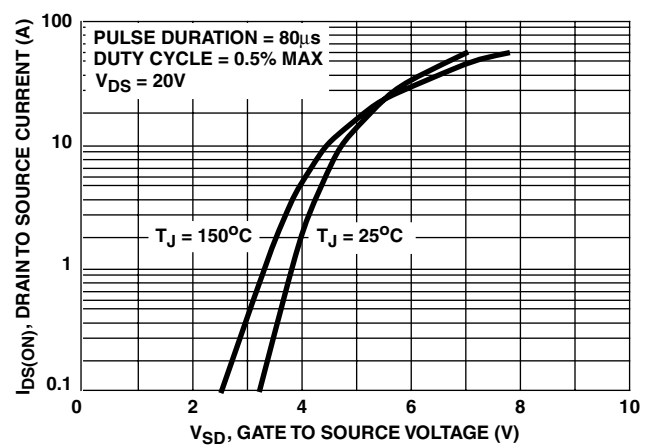


FIGURE 7. TRANSFER CHARACTERISTICS

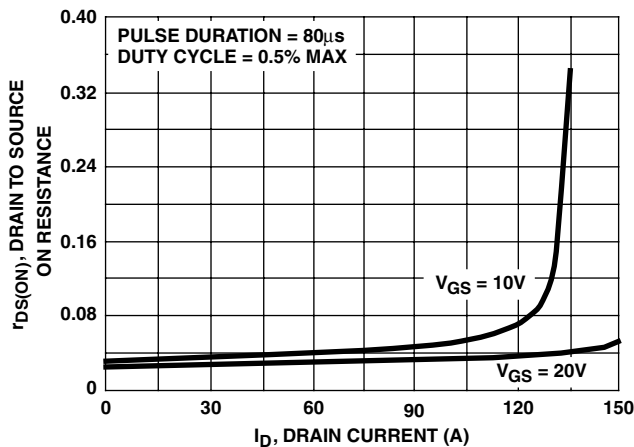


FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs. GATE VOLTAGE AND DRAIN CURRENT

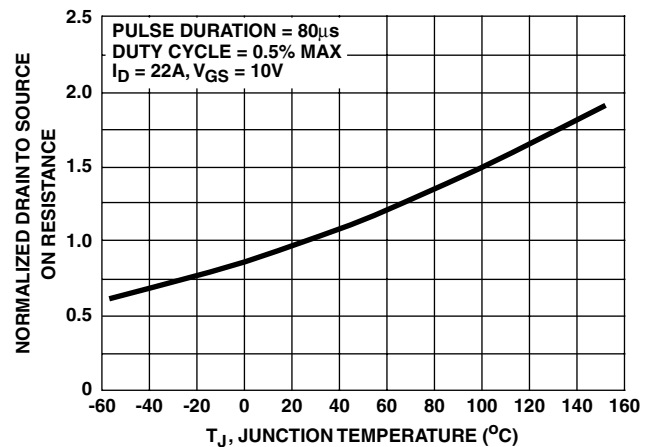


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs. JUNCTION TEMPERATURE

**Typical Performance Curves** Unless Otherwise Specified (Continued)

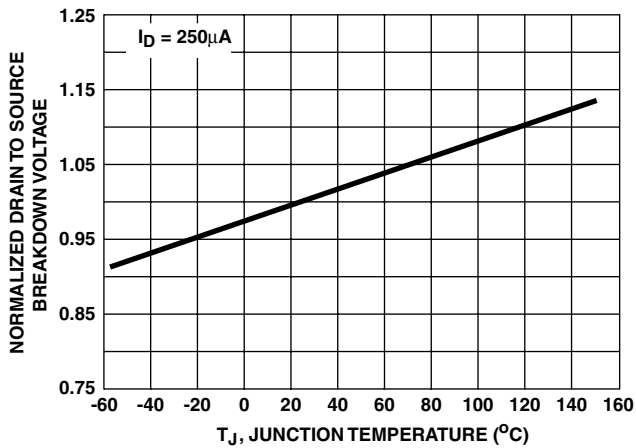


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

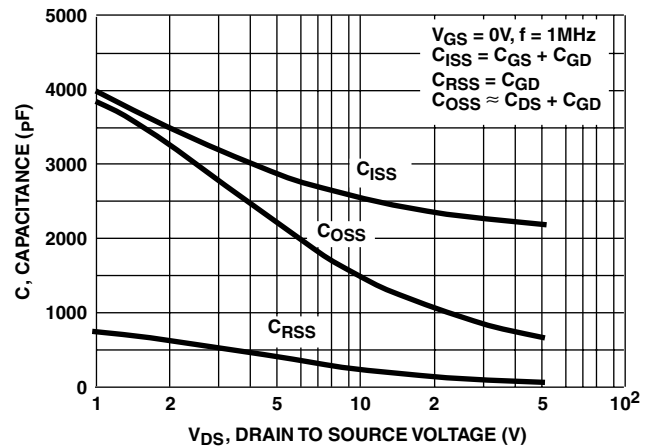


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

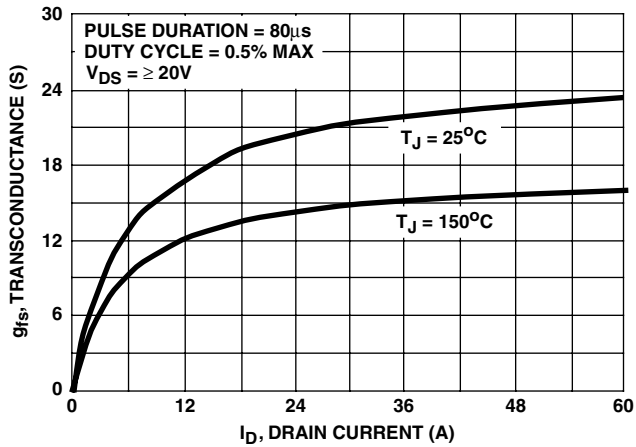


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

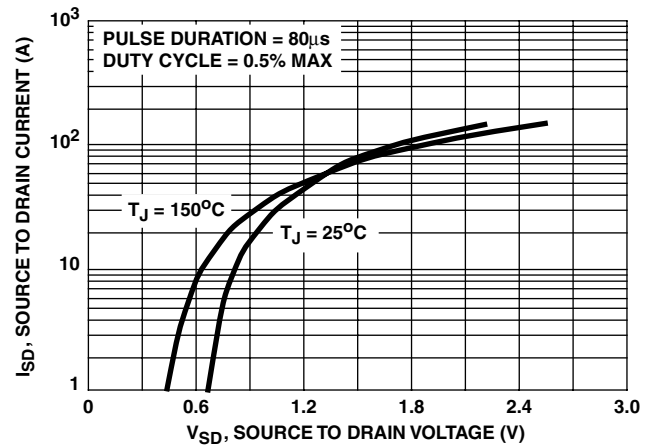


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

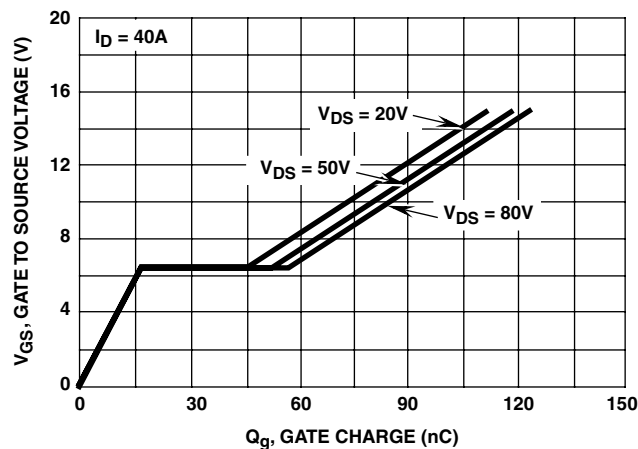


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

## Test Circuits and Waveforms

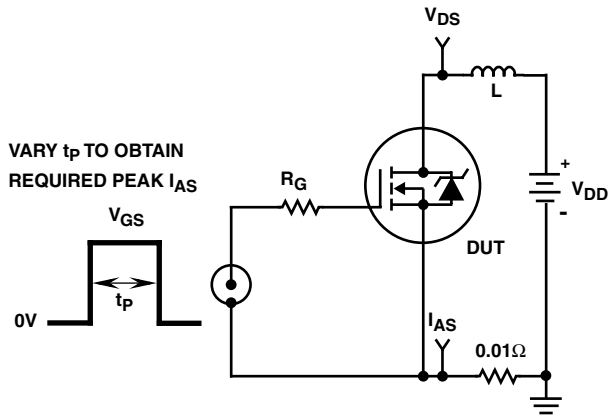


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

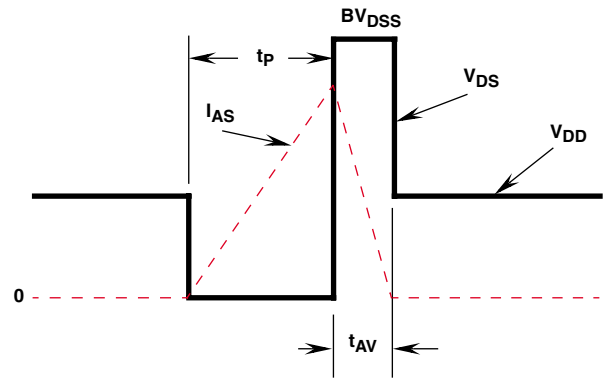


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

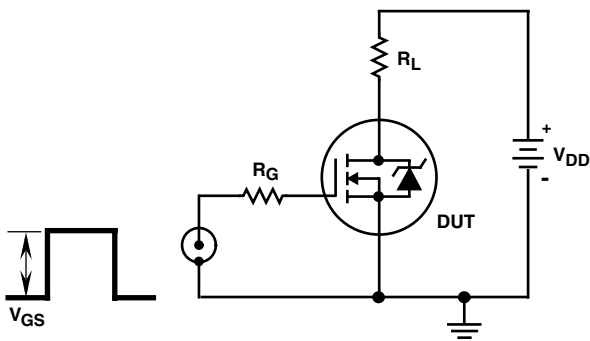


FIGURE 17. SWITCHING TIME TEST CIRCUIT

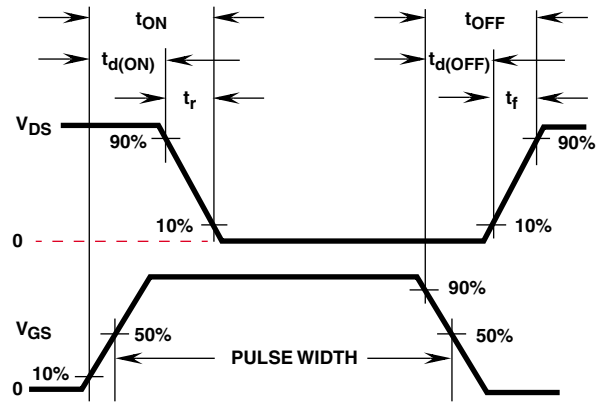


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

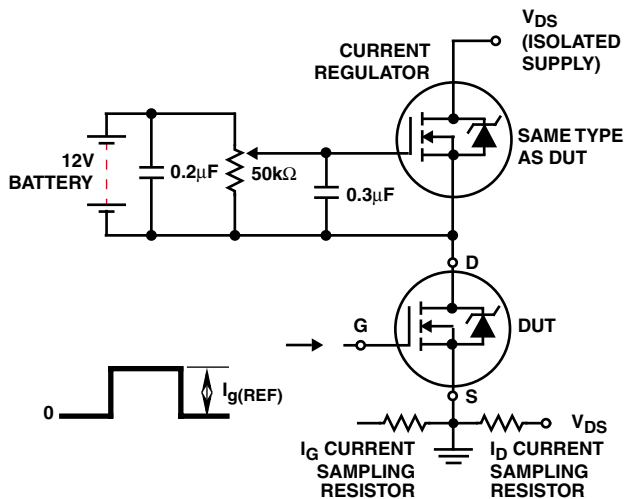


FIGURE 19. GATE CHARGE TEST CIRCUIT

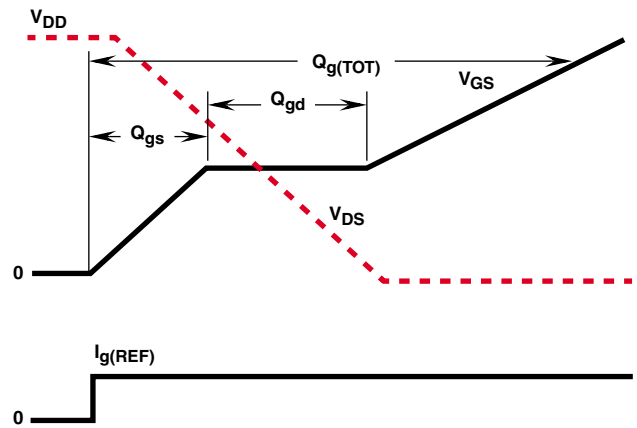


FIGURE 20. GATE CHARGE WAVEFORMS

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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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